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Application/Control No.	Applicant(s)/Patent under Reexamination
10/616,716	ADACHI ET AL.
Examiner	Art Unit

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Cynthia Lee	1745	

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Class	Subclass	Date	Examiner
429	231.95	4/21/2006	CL
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SEARCH I (INCLUDING SEAR)
	DATE	EXMR
PLUS search	4/10/2006	CL
inventor search	4/10/2006	CL
EAST search	4/10/2006	CL
STIC search	4/18/2006	CL
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